

**Notice of References Cited**

Application/Control No.

10/757,270

Applicant(s)/Patent Under  
Reexamination  
DI LUOFFO ET AL.

Examiner

Djenane M. Bayard

Art Unit

2141

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,594,684	07-2003	Hodjat et al.	709/202
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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